

IN THE SPECIFICATION

At page 1, on a separate line appearing immediately after the title, insert:

--This application is a division of Application No. 09/506,289, filed February 18, 2000.--

Please amend the paragraph appearing from page 77, line 14 to page 78, line 2, as follows:

Furthermore, it was found out that no region having high resistance did not exist in the carbon films 15 as a result of observation through an interatomic force/tunnel microscope having an interatomic force microscope probe (also referred to as an “Atomic Force Microscope (AFM)”) which was made electrically conductive so that an electrical conductivity distribution of a sample could be measured with the sample kept in contact with the probe. Furthermore, the probe was kept in contact with the carbon films 15 disposed on the electrically conductive film 14 during the measurement. An evaluation of specific resistance in a direction of width of the film provided a result not higher than 0.001  $\Omega$ m. Comparison of this value with that of a carbon film 15 which was formed without irradiation with electrons indicated a variation exceeding a place.